

<b>Notice of References Cited</b>	Application/Control No. 10/034,696	Applicant(s)/Patent Under Reexamination PAVLIDIS, IOANNIS	
	Examiner Christopher L. Lavin	Art Unit 2621	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Stein "Tracking from multiple view points: Self-calibration of space and time", Computer Vision and Pattern Recognition, 1999, IEEE Computer Society Conference on, Volume 1, 23-25 June 1999 Page(s): 521 - 527
	V	
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